Future of Power Efficient Processing



Dr. Michael Fritze
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Power Efficient Electronics are Critical to Many DoD Missions



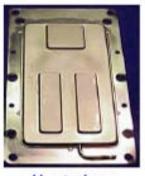
Soldiers carry packs in 70-120 lbs range Frequently 10-20 lbs are batteries!

Power is frequently scarce and expensive: UAVs, remote sensor networks, space, etc.



DSRC Summer 2006 Low Power Workshop

Getting rid of dissipated heat is often a major problem by itself!

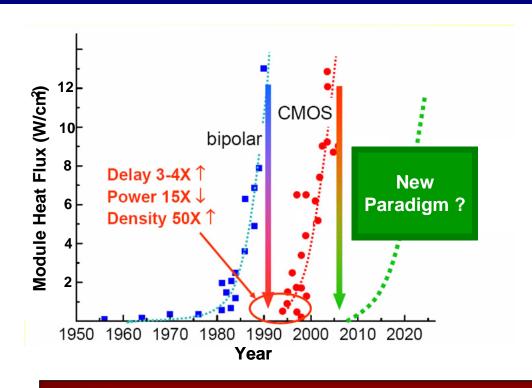


Heat pipes



Electronics History: Power Efficiency Perspective





Power = Dynamic + Static = $0.5CV_{dd}^2f + I_{leak}V_{dd}$

Ultimate Goals:

No performance penalty

- Each technology ultimately reaches integration density limited by power dissipation
- Quantum jump then occurs to new technology with lower power

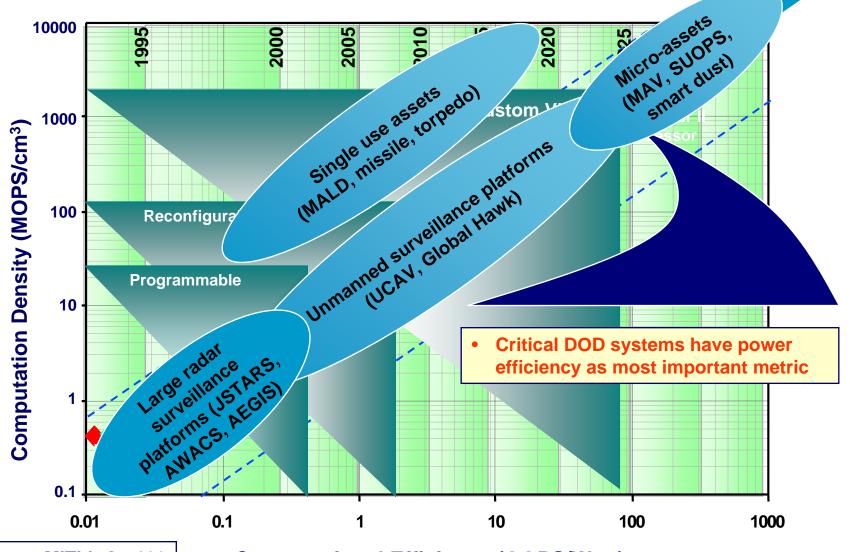
Time for the next paradigm change?



Embedded Computing for DoD



Power Efficiency (Ops/Watt) is Key



J. Anderson, MITLL Gp 102 HPEC Conference '04-'05 **Computational Efficiency (GOPS/Watt)**



Some Paths Forward: Power Efficiency

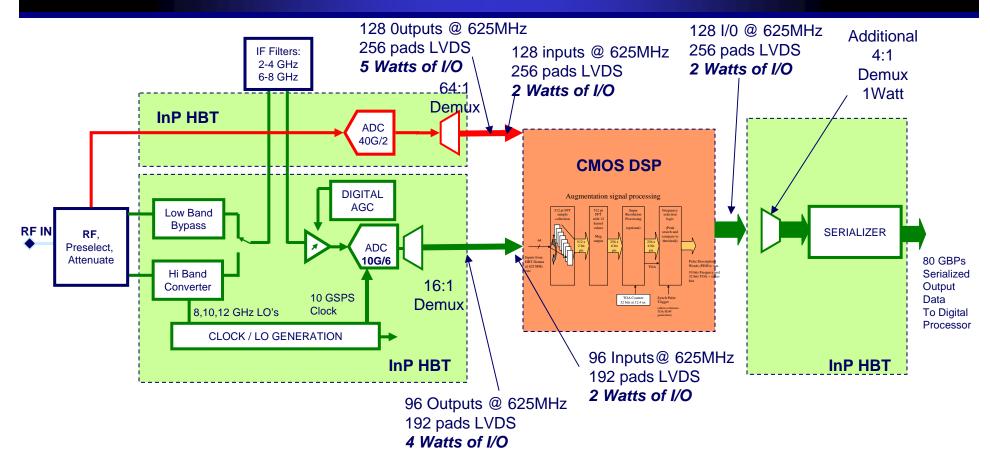


- I) Densely integrated RF technology
 - RF SOC vs MCM implementation
 - 'TEAM'
- II) Novel Architecture/Design
 - Power management
 - Sub-threshold, Parallelism, 3D
 - 'ESE', '3D-IC'
- III) Ultra-low power CMOS
 - Tunable threshold
 - Steeper sub-threshold slope (< 62 mV/dec)
 - 'STEEP' BAA coming out
- IV) Beyond Silicon
 - Carbon electronics
 - Graphene, Nanotubes
 - Workshop in early April



Power Benefits of Integration: RF-SOC vs. MCM





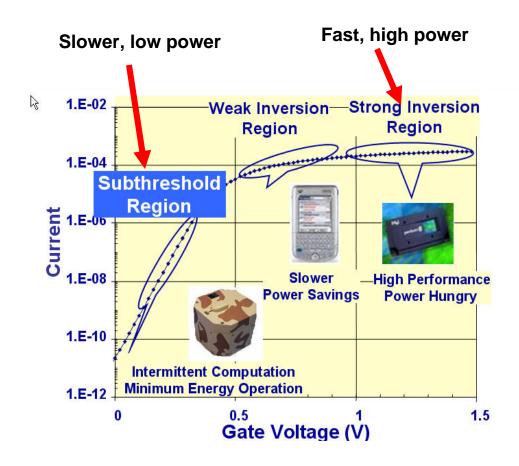
All four ICs can be implemented in a single SiGe IC

... 16 Watts of additional power due to intra-chip I/O in multi-chip approach over a monolithic implementation



Sub-threshold Digital Design: Energy Starved Electronics (ESE) Program





PI: Prof. Anantha Chandrakasan, MIT Fab: TI, Dr. Dennis Buss, 65-nm CMOS

• <u>Goal</u>: Enable ultra-low power digital circuits operating in the *sub-threshold regime* while maintaining adequate performance. Energy consumption savings > 10X.

Technical Challenges:

- Develop standard cells operating at V_{dd}
 < 300 mV; esp. SRAM
- Achieving adequate performance (through parallelism)
- Addressing high sensitivity to variations (via ECC)

Design Only Approach:

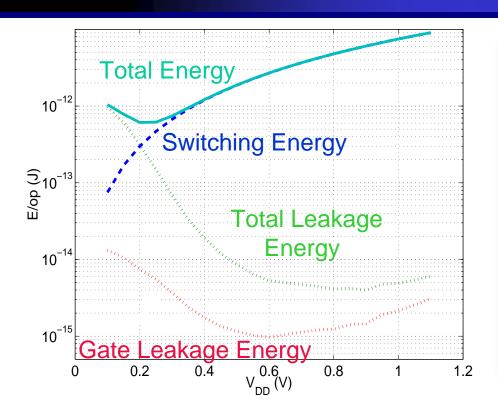
- No device technology changes
- Exploits massive investment by industry for DoD benefit

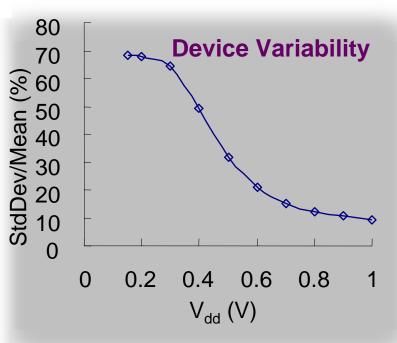


Minimum Energy Point:



Switching vs. Leakage





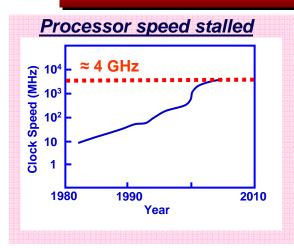
- •Minimum energy point ≈ 200 mV (sub-threshold regime)
 - •Must be compensated for (e.g., parallelism and threshold control)
 - •Optimum voltage V_{dd} varies with circuit activity
- •Leakage energy increases at extremely low voltages (long delay times)
- •Increased variability requires wider margins, reduced performance

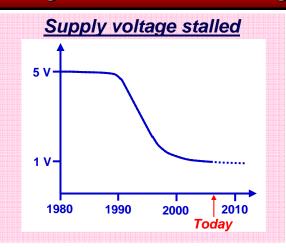


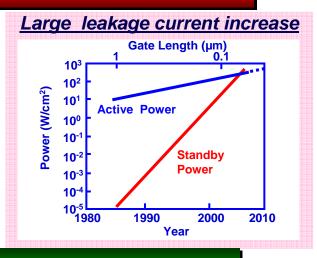
Steep-subthreshold-slope Transistors for Electronics with Extremely-low Power (STEEP)



Problem: Device Scaling alone will no longer meet DoD needs!







Proposed Solution: Steep-subthreshold-slope Transistors

Subthreshold Swing = 62 mV/dec (FDSOI) = 90 mV/dec (Bulk) Turn-on voltage ~ 1 V

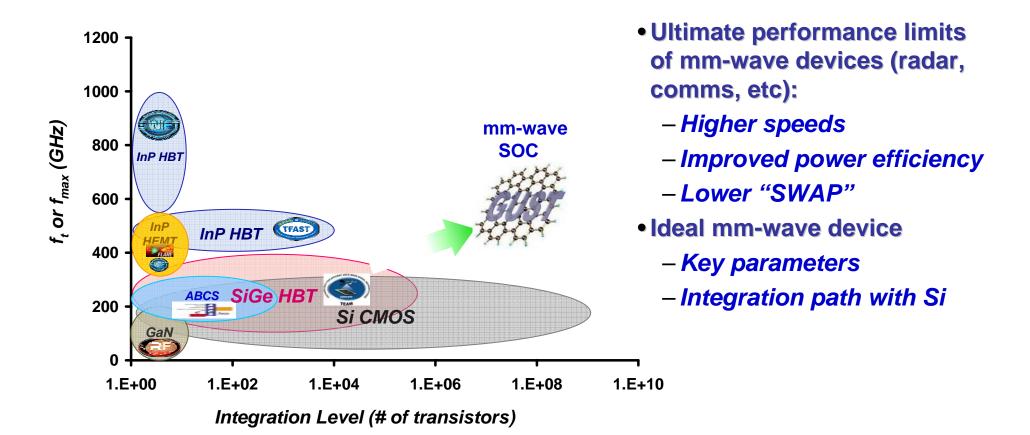
Theoretical minimum of the subthreshold swing of MOSFET is In10(kT/q) or 60 mV/dec

STEEP Vision



Develop ideal transistor switch for ultra-low power electronics

Carbon Electronics: High Performance & Integration for RF-SOC's

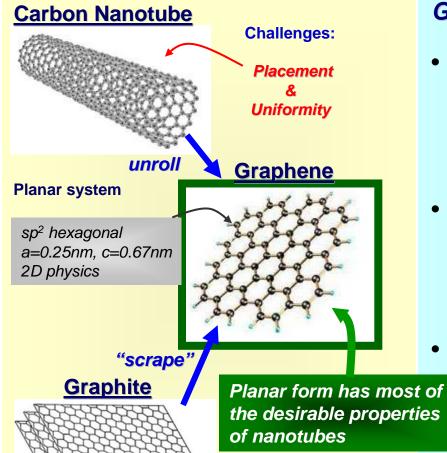


New Opportunity: Carbon-based mm-wave SOC's



New Approach For Ideal mm-wave Material: Planar Carbon (Graphene)





Graphene Properties:

- High mobilities for both <u>electron & hole</u>
 (> 10X silicon)
 - $-\mu \ge 15,000 \text{ cm}^2/\text{Vs, } m^* = 0.06m_0$
 - mm-wave & low power potential
 - High current density
- Ideal electrostatics ("monolayer-oninsulator")
 - Sub-nm thickness
 - < Debye screening length
 - Enables aggressive scaling
- Planar processing can be used
 - Standard paradigm
 - Straightforward integration with CMOS

Semimetal band structure

I_{or}/I_{off} ~ 30, useful for RF devices

Graphene is very promising material for mm-wave RF-SOC technology



A Possible Path Forward



